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This is the AES handbook. This is important for surface science and surface analysis research. This is an important guide to qualitative and quantitative analysis, as well as interpreting the objectives of our CMA and SCA-based AES users. It includes the various data needed for Auger's electronic spectroscopy, such as derivative type and integral spectrums, weak spectrum auger peak, and high kinetic energy data region. PHI quantesphi quanterra II™PHI 5000 VersaProbe IIPHI X-tool Learn about the Virtual Library Leaders Forum takes place this month December 15, 2009 Editing WorkBot Link runs April 30, 2008 Created by an anonymous user imported from amazon.com records. Kenton's book David Childs, Brad Carlson, Laurie A LaVanier, Carol L Hedberg Published in 1995 in Eden Prairie (Minn) on Physical Electronics Services Handbook Detailed Information Handbook X-ray photovoltaic spectroscopy contains reference spectra from standard samples and compilations of expected peak positions and binding energy shifts that can be used as a guide for elementary and chemical interpretation. The guide contains spectra derived from al monochrome X-ray source and mg chromatic X-ray source Mg. The introductory section provides a brief overview of the basics of XPS and the types of spectral functions that can be encountered when interpreting XPS spectrums. This guide can be seen in the physical electronics parts department in Chanhassen, Minnesota. Email us at parts@phi.com for more information. The Auger Electron Spectroscopy Handbook contains reference spectra from standard samples and compilations of expected peak positions that can be used by management for elementary peak identification. The first full-spectrum derivative is displayed along with selected areas of interest in direct and first-rate modes. The introduction section provides a brief overview of the basics of AES. In addition, the handbook includes a discussion on quantitative evaluation and diagrams containing relative factors of elementary sensitivity. Appendix A provides a comparison of spectrums on spectrums of 3, 5 and 10 kv. This guide can be seen in the physical electronics parts department in Chanhassen, Minnesota. Email us at parts@phi.com for more information. Click here to buy J. Moulder et al. X-ray Spectroscopy (XPS) (1992, 1995). ISBN: 0-9627026-2-5 This is a guide to standard spectra for identification and interpretation of XPS data. It contains the spectra of almost al natural elements. The spectra from this element are built on two facing pages, with the spectrum on the left page coming from the al-chromatic source, that on the right page the time from the source of Mg. High-resolution energy spectrums of the main transport are also shown as howl, basic peak energy (including the main Auger Auger and the plot of some chemical effects. The book also contains many phases of the Auger parameter, chemical status and reference tables, sensitivity factors for two sources angles, peak energies for Al and Mg X-rays, and peak energies in numerical order. The 1995 version is a reissue of the 1992 version with some minor changes. This XPS GUIDE is \$545.00 for shipping to the U.S. This XPS guide is \$595.00 for shipping outside the U.S. If you want to continue shopping and you get a message that the web page is trying to close the window, choose Yes. You can continue shopping by adding extra items to your shopping cart. Any previously added items should remain in your shopping cart. Note: The buyer is responsible for any sale or use of the tax. Click here to buy the Auger Handbook of Electronic Spectroscopy (AES) by C.D. Childs et al (1995). ISBN: 0-9648124-0-1 This is the third edition of this guide and contains many updates and a few additional elements. The reference spectra were obtained using a cylindrical mirror analyzer (CMA) with an electronic beam energy of 10 square meters. The spectra were taken in direct mode and numerically differentiated using the 5-ton filter Sovitsky-Golai. Both derivatives and direct spectrums are built. Scale factors are included for each spectrum. The book also contains a comparison of derivative spectra using 3, 5 and 10 energy beam keV incidents. A table of possible elements found as a function of measured kinetic energy is also included, as are tables and sections of Auger sensitivity factors. 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